## Features

- 3.0V to 5.5V Operating Range
- Advanced Low-voltage, Zero-power, Electrically Erasable Programmable Logic Device
- Edge-sensing "Zero" Power
- Low-voltage Equivalent of ATF22V10CZ
- "Zero" Standby Power ( 25 $\mu \mathrm{A}$ Maximum) (Input Transition Detection)
- Ideal for Battery Powered Systems
- CMOS- and TTL-compatible Inputs and Outputs
- Latch Feature Hold Inputs to Previous Logic States
- Advanced EE Technology
- Reprogrammable
- 100\% Tested
- High-reliability CMOS Process
- 20-year Data Retention
- 100 Erase/Write Cycles
- 2,000V ESD Protection
- 200 mA Latch-up Immunity
- Commercial and Industrial Temperature Ranges
- Dual Inline and Surface Mount Standard Pinouts
- Inputs are 5V Tolerant


## Block Diagram



Pin Configurations
All Pinouts Top View

| Pin Name | Function |
| :--- | :--- |
| CLK | Clock |
| IN | Logic Inputs |
| I/O | Bi-directional Buffers |
| GND | Ground |
| VCC | (3 to 5.5 V ) Supply |
| PLCC |  |



Note: For PLCC, pins 1, 8, 15, and 22 can be left unconnected. For superior performance, connect VCC to pin 1 and GND to pins 8, 15, and 22.


Note: TSSOP is the smallest package of SPLD offering.

DIP/SOIC


## Description

The ATF22LV10CZ/CQZ is a high-performance CMOS (electrically erasable) programmable logic device (PLD) that utilizes Atmel's proven electrically erasable Flash memory technology and provides 25 ns speed with standby current of $25 \mu \mathrm{~A}$ maximum. All speed ranges are specified over the 3.0 V to 5.5 V range for industrial and commercial temperature ranges.

The ATF22LV10CZ/CQZ provides a low-voltage and edgesensing "zero" power CMOS PLD solution with "zero" standby power ( $5 \mu \mathrm{~A}$ typical). The ATF22LV10CZ/CQZ powers down automatically to the zero power mode through Atmel's patented Input Transition Detection (ITD) circuitry when the device is idle. The ATF22LV10CZ/CQZ is capable of operating at supply voltages down to 3.0 V .

Pin "keeper" circuits on input and output pins hold pins to their previous logic levels when idle, which eliminate static power consumed by pull-up resistors. The "CQZ" combines this low high-frequency $\mathrm{I}_{\mathrm{CC}}$ of the " Q " design with the " Z " feature.
The ATF22LV10CZ/CQZ macrocell incorporates a variable product term architecture. Each output is allocated from 8 to 16 product terms which allows highly complex logic functions to be realized. Two additional product terms are included to provide synchronous reset and asynchronous reset. These additional product terms are common to all 10 registers and are automatically cleared upon power-up. Register Preload simplifies testing. A security fuse prevents unauthorized copying of programmed fuse patterns.

## Absolute Maximum Ratings*

| Temperature under Bias .............................. $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ |  |
| :---: | :---: |
| Storage Temperature ..... | .... $-65^{\circ} \mathrm{C}$ to $+150^{\circ} \mathrm{C}$ |
| Voltage on Any Pin with |  |
| Respect to Ground . | ...-2.0V to $+7.0 \mathrm{~V}^{(1)}$ |
| Voltage on Input Pins with Respect to Ground during Programming ........ | $\ldots .-2.0 \mathrm{~V} \text { to }+14.0 \mathrm{~V}^{(1)}$ |
| Programming Voltage with |  |
| Respect to Ground ........... | $\ldots-2.0 \mathrm{~V}$ to $+14.0 \mathrm{~V}^{(1)}$ |

> *NOTICE: Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Note: 1. Minimum voltage is -0.6 V DC, which may undershoot to -2.0V for pulses of less than 20 ns . Maximum output pin voltage is $\mathrm{V}_{\mathrm{CC}}+0.75 \mathrm{~V}$ DC, which may overshoot to 7.0 V for pulses of less than 20 ns .

## DC and AC Operating Conditions

|  | Commercial | Industrial |
| :--- | :---: | :---: |
| Operating Temperature (Ambient) | $0^{\circ} \mathrm{C}-70^{\circ} \mathrm{C}$ | $-40^{\circ} \mathrm{C}-85^{\circ} \mathrm{C}$ |
| $\mathrm{V}_{\mathrm{CC}}$ Power Supply | $3.0 \mathrm{~V}-5.5 \mathrm{~V}$ | $3.0 \mathrm{~V}-5.5 \mathrm{~V}$ |

## Functional Logic Diagram Description

The Functional Logic Diagram describes the ATF22LV10CZ/CQZ architecture.
The ATF22LV10CZ/CQZ has 12 inputs and 10 I/O macrocells. Each macrocell can be configured into one of four output configurations: active high/low or registered/combinatorial. The universal architecture of the ATF22LV10CZ/CQZ can be programmed to emulate most 24-pin PAL devices.

Unused product terms are automatically disabled by the compiler to decrease power consumption. A security fuse, when programmed, protects the contents of the ATF22LV10CZ/CQZ. Eight bytes (64 fuses) of User Signature are accessible to the user for purposes such as storing project name, part number, revision or date. The User Signature is accessible regardless of the state of the security fuse.

## DC Characteristics

| Symbol | Parameter | Condition ${ }^{(2)}$ |  |  | Min | Typ | Max | Units |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{I}_{\text {IL }}$ | Input or I/O Low Leakage Current | $0 \leq \mathrm{V}_{\text {IN }} \leq \mathrm{V}_{\text {IL }}$ (Max) |  |  |  |  | -10.0 | $\mu \mathrm{A}$ |
| $\mathrm{I}_{\mathrm{IH}}$ | Input or I/O High Leakage Current | $\left(\mathrm{V}_{\mathrm{CC}}-0.2\right) \mathrm{V} \leq \mathrm{V}_{\mathrm{IN}} \leq \mathrm{V}_{\mathrm{CC}}$ |  |  |  |  | 10.0 | $\mu \mathrm{A}$ |
| $\mathrm{I}_{\mathrm{CC}}$ | Clocked Power Supply Current | $\mathrm{V}_{\mathrm{CC}}=\operatorname{Max}$ <br> Outputs Open, $\mathrm{f}=15 \mathrm{MHz}$ | CZ-25 | Com. |  | 50.0 | 85.0 | mA |
|  |  |  | CZ-25 | Ind. |  | 55.0 | 90.0 | mA |
|  |  |  | CQZ-25 | Com. |  | 18.0 | 50.0 | mA |
|  |  |  | CQZ-25 | Ind. |  | 19.0 | 60.0 | mA |
| $\mathrm{I}_{\text {SB }}$ | Power Supply Current, Standby | $\begin{aligned} & \mathrm{V}_{\mathrm{CC}}=\mathrm{Max} \\ & \mathrm{~V}_{\mathrm{IN}}=\mathrm{Max} \\ & \text { Outputs Open } \end{aligned}$ | CZ-25 | Com. |  | 3.0 | 25.0 | $\mu \mathrm{A}$ |
|  |  |  | CZ-25 | Ind. |  | 4.0 | 50.0 | $\mu \mathrm{A}$ |
|  |  |  | CQZ-25 | Com. |  | 3.0 | 25.0 | $\mu \mathrm{A}$ |
|  |  |  | CQZ-25 | Ind. |  | 4.0 | 50.0 | $\mu \mathrm{A}$ |
| $\mathrm{IOS}^{(1)}$ | Output Short Circuit Current | $\mathrm{V}_{\text {OUT }}=0.5 \mathrm{~V}$ |  |  |  |  | -130.0 | mA |
| $\mathrm{V}_{\text {IL }}$ | Input Low Voltage |  |  |  | -0.5 |  | 0.8 | V |
| $\mathrm{V}_{\mathrm{IH}}$ | Input High Voltage |  |  |  | 2.0 |  | $\mathrm{V}_{\mathrm{CC}}+0.75$ | V |
| $\mathrm{V}_{\mathrm{OL}}$ | Output Low Voltage | $\begin{aligned} & \mathrm{V}_{\mathrm{IN}}=\mathrm{V}_{\mathrm{IH}} \text { or } \mathrm{V}_{\mathrm{IL}} \\ & \mathrm{~V}_{\mathrm{CC}}=\mathrm{Min}, \\ & \mathrm{I}_{\mathrm{OL}}=16 \mathrm{~mA} \end{aligned}$ | Com. |  |  |  | 0.5 | V |
|  |  |  | Ind. |  |  |  |  |  |
| $\mathrm{V}_{\mathrm{OH}}$ | Output High Voltage | $\begin{aligned} & \mathrm{V}_{\mathrm{IN}}=\mathrm{V}_{\mathrm{IH}} \text { or } \mathrm{V}_{\mathrm{IL}} \\ & \mathrm{~V}_{\mathrm{CCIO}}=\mathrm{Min}, \\ & \mathrm{I}_{\mathrm{OH}}=-2.0 \mathrm{~mA} \end{aligned}$ |  |  | 2.4 |  |  | V |
| $\mathrm{V}_{\mathrm{OH}}$ | Output High Voltage | $\mathrm{I}_{\mathrm{OH}}=-100 \mu \mathrm{~A}$ |  |  | $\mathrm{V}_{\mathrm{CC}}-0.2 \mathrm{~V}$ |  |  | V |

Notes: 1. Not more than one output at a time should be shorted. Duration of short circuit test should not exceed 30 sec.
2. For DC characterization, the test condition of $\mathrm{V}_{\mathrm{CC}}=\mathrm{Max}$ corresponds to 3.6 V .

## AC Waveforms

INPUTS, I/O REG. FEEDBACK SYNCH. PRESET


## AC Characteristics ${ }^{(1)}$

| Symbol | Parameter | -25 |  | -30 |  | Units |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | Min | Max | Min | Max |  |
| $\mathrm{t}_{\text {PD }}$ | Input or Feedback to Non-registered Output | 3.0 | 25.0 | 10.0 | 30.0 | ns |
| $\mathrm{t}_{\mathrm{CF}}$ | Clock to Feedback |  | 13.0 | 10.0 | 15.0 | ns |
| $\mathrm{t}_{\mathrm{CO}}$ | Clock to Output | 2.0 | 15.0 | 4.0 | 20.0 | ns |
| $\mathrm{t}_{\text {s }}$ | Input or Feedback Setup Time | 15.0 |  | 18.0 |  | ns |
| $\mathrm{t}_{\mathrm{H}}$ | Input Hold Time | 0 |  | 0 |  | ns |
| $t_{P}$ | Clock Period | 25.0 |  | 30.0 |  | ns |
| $\mathrm{t}_{\mathrm{w}}$ | Clock Width | 12.5 |  | 15.0 |  | ns |
| $\mathrm{f}_{\text {MAX }}$ | External Feedback $1 /\left(t_{s}+t_{c o}\right)$ Internal Feedback $1 /\left(\mathrm{t}_{\mathrm{S}}+\mathrm{t}_{\mathrm{CF}}\right)$ No Feedback 1/(tp) | $\begin{aligned} & 33.3 \\ & 35.7 \\ & 40.0 \end{aligned}$ |  |  | $\begin{aligned} & 25.0 \\ & 30.0 \\ & 33.3 \end{aligned}$ | $\begin{aligned} & \mathrm{MHz} \\ & \mathrm{MHz} \\ & \mathrm{MHz} \end{aligned}$ |
| $t_{\text {EA }}$ | Input to Output Enable | 3.0 | 25.0 | 10.0 | 30.0 | ns |
| $\mathrm{t}_{\mathrm{ER}}$ | Input to Output Disable | 3.0 | 25.0 | 10.0 | 30.0 | ns |
| $\mathrm{t}_{\text {AP }}$ | Input or I/O to Asynchronous Reset of Register | 3.0 | 25.0 | 10.0 | 3.0 | ns |
| $\mathrm{t}_{\mathrm{SP}}$ | Setup Time, Synchronous Preset | 15.0 |  | 20.0 |  | ns |
| $t_{\text {AW }}$ | Asynchronous Reset Width | 25.0 |  | 30.0 |  | ns |
| $\mathrm{t}_{\text {AR }}$ | Asynchronous Reset Recovery Time | 25.0 |  | 30.0 |  | ns |
| $\mathrm{t}_{\text {SPR }}$ | Synchronous Preset to Clock Recovery Time | 15.0 |  | 20.0 |  | ns |

Note: 1. See ordering information for valid part numbers.

## Input Test Waveforms and Measurement Levels



DRIVING LEVELS

$\mathrm{t}_{\mathrm{r}}, \mathrm{t}_{\mathrm{f}} \leq 1.5 \mathrm{~ns}$

## Output Test Loads



Note: Similar competitors devices are specified with slightly different loads. These load differences may affect output signals' delay and slew rate. Atmel devices are tested with sufficient margins to meet compatible device specification conditions.

## Pin Capacitance

$\mathrm{f}=1 \mathrm{MHz}, \mathrm{T}=25^{\circ} \mathrm{C}^{(1)}$

|  | Typ | Max | Units | Conditions |
| :--- | :---: | :---: | :---: | :---: |
| $\mathrm{C}_{\mathrm{IN}}$ | 5 | 8 | pF | $\mathrm{V}_{\text {IN }}=0 \mathrm{~V}$ |
| $\mathrm{C}_{\mathrm{I} / \mathrm{O}}$ | 6 | 8 | pF | $\mathrm{V}_{\text {OUT }}=0 \mathrm{~V}$ |

Notes: 1. Typical values for nominal supply voltage. This parameter is only sampled and is not $100 \%$ tested.

## Power-up Reset

The registers in the ATF22LV10CZ/CQZ are designed to reset during power-up. At a point delayed slightly from $\mathrm{V}_{\mathrm{CC}}$ crossing $\mathrm{V}_{\mathrm{RST}}$, all registers will be reset to the low state. The output state will depend on the polarity of the buffer.
This feature is critical for state machine initialization. However, due to the asynchronous nature of reset and the uncertainty of how $\mathrm{V}_{\mathrm{CC}}$ actually rises in the system, the following conditions are required:

1. The $\mathrm{V}_{\mathrm{CC}}$ rise must be monotonic and start below 0.7 V .
2. The clock must remain stable during $\mathrm{T}_{\mathrm{PR}}$.
3. After $T_{P R}$, all input and feedback setup times must be met before driving the clock pin high.

## Preload of Register Outputs

The ATF22LV10CZ/CQZ's registers are provided with circuitry to allow loading of each register with either a high or a low. This feature will simplify testing since any state can be forced into the registers to control test sequencing. A JEDEC file with preload is generated when a source file with vectors is compiled. Once downloaded, the JEDEC file preload sequence will be done automatically by most of the approved programmers after the programming.

## Electronic Signature Word

There are 64 bits of programmable memory that are always available to the user, even if the device is secured. These bits can be used for user-specific data.

## Security Fuse Usage

A single fuse is provided to prevent unauthorized copying of the ATF22LV10CZ/CQZ fuse patterns. Once programmed, fuse verify and preload are inhibited. However, the 64-bit User Signature remains accessible.
The security fuse should be programmed last, as its effect is immediate.

## Programming/Erasing

Programming/erasing is performed using standard PLD programmers. See CMOS PLD Programming Hardware \& Software Support for information on software/ programming.

| Parameter | Description | Typ | Max | Units |
| :--- | :--- | :---: | :---: | :---: |
| $\mathrm{T}_{\mathrm{PR}}$ | Power-up <br> Reset Time | 600 | 1000 | ns |
| $\mathrm{~V}_{\mathrm{RST}}$ | Power-up <br> Reset Voltage | 2.3 | 2.7 | V |

## Input and I/O Pin Keepers

All ATF22LV10CZ/CQZ family members have internal input and I/O pin-keeper circuits. Therefore, whenever inputs or I/Os are not being driven externally, they will maintain their last driven state. This ensures that all logic array inputs and
device outputs are at known states. These are relatively weak active circuits that can be easily overridden by TTLcompatible drivers (see input and I/O diagrams below).

Input Diagram


## I/O Diagram



Functional Logic Diagram ATF22LV10CZ/CQZ


ATF22LV10CZCQZ STANDBY CURRENT VS. SUPPLY VOLTAGE ( $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$ )


ATF22LV10CZ SUPPLY CURRENT VS. INPUT FREQUENCY $\left(\mathrm{V}_{\mathrm{CC}}=\mathbf{3 . 3 V}, \mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}\right)$


ATF22LV10CZCQZ SOURCE CURRENT VS. SUPPLY VOLTAGE ( $\mathrm{V}_{\mathrm{OH}}=2.4 \mathrm{~V}$ )










NORMALIZED $T_{c o}$ VS. TEMP



22LV10CZ/CQZ DELTA TPD VS.
OUTPUT LOADING


DELTA TPD ${ }_{\text {PD }}$ \# OF OUTPUT SWITCHING


22LV10CZ/CQZ DELTA T ${ }_{\text {Co }}$ VS. OUTPUT LOADING


DELTA Th $_{\text {co }}$ VS. \# OF OUTPUT SWITCHING


## Ordering Information

| $\mathrm{t}_{\mathrm{PD}}$ ( ns ) | $\mathrm{t}_{\mathrm{S}}$ ( ns ) | $\mathrm{t}_{\mathrm{co}}$ (ns) | Ordering Code | Package | Operation Range |
| :---: | :---: | :---: | :---: | :---: | :---: |
| 25 | 15 | 15 | ATF22LV10CZ-25JC <br> ATF22LV10CZ-25PC <br> ATF22LV10CZ-25SC <br> ATF22LV10CZ-25XC | $\begin{aligned} & 28 \mathrm{~J} \\ & 24 \mathrm{P} 3 \\ & 24 \mathrm{~S} \\ & 24 \mathrm{X} \end{aligned}$ | Commercial $\left(0^{\circ} \mathrm{C}\right.$ to $\left.70^{\circ} \mathrm{C}\right)$ |
|  |  |  | ATF22LV10CZ-25JI <br> ATF22LV10CZ-25PI <br> ATF22LV10CZ-25SI <br> ATF22LV10CZ-25XI | $\begin{aligned} & 28 \mathrm{~J} \\ & 24 \mathrm{P} 3 \\ & 24 \mathrm{~S} \\ & 24 \mathrm{X} \end{aligned}$ | Industrial $\left(-40^{\circ} \mathrm{C} \text { to }+85^{\circ} \mathrm{C}\right)$ |
|  |  |  | ATF22LV10CQZ-30JC <br> ATF22LV10CQZ-30PC <br> ATF22LV10CQZ-30SC <br> ATF22LV10CQZ-30XC | $\begin{aligned} & 28 \mathrm{~J} \\ & 24 \mathrm{P3} \\ & 24 \mathrm{~S} \\ & 24 \mathrm{X} \end{aligned}$ | Commercial $\left(0^{\circ} \mathrm{C}\right.$ to $\left.70^{\circ} \mathrm{C}\right)$ |
|  |  |  | ATF22LV10CQZ-30JI ATF22LV10CQZ-30PI ATF22LV10CQZ-30SI ATF22LV10CQZ-30XI | $\begin{aligned} & 28 \mathrm{~J} \\ & 24 \mathrm{P} 3 \\ & 24 \mathrm{~S} \\ & 24 \mathrm{X} \end{aligned}$ | $\begin{gathered} \text { Industrial } \\ \left(-40^{\circ} \mathrm{C} \text { to }+85^{\circ} \mathrm{C}\right) \end{gathered}$ |

## Using "C" Product for Industrial

To use commercial product for industrial temperature ranges, simply de-rate $I_{C c}$ by $15 \%$ on the " $C$ " device. No speed de-rating is necessary.

| Package Type |  |
| :--- | :--- |
| $\mathbf{2 8 J}$ | 28-lead, Plastic J-leaded Chip Carrier (PLCC) |
| $\mathbf{2 4 P 3}$ | 24-pin, 0.300" Wide, Plastic Dual Inline Package (PDIP) |
| $\mathbf{2 4 S}$ | 24-lead, 0.300" Wide, Plastic Gull Wing Small Outline (SOIC) |
| $\mathbf{2 4 X}$ | 24-lead, 4.4 mm Wide, Plastic Thin Shrink Small Outline (TSSOP) |

Packaging Information


## Atmel Headquarters

## Corporate Headquarters

 2325 Orchard Parkway San Jose, CA 95131 TEL (408) 441-0311FAX (408) 487-2600

## Europe

Atmel SarL
Route des Arsenaux 41
Casa Postale 80
CH-1705 Fribourg
Switzerland
TEL (41) 26-426-5555
FAX (41) 26-426-5500
Asia
Atmel Asia, Ltd.
Room 1219
Chinachem Golden Plaza
77 Mody Road Tsimhatsui
East Kowloon
Hong Kong
TEL (852) 2721-9778
FAX (852) 2722-1369

## Japan

Atmel Japan K.K.
9F, Tonetsu Shinkawa Bldg.
1-24-8 Shinkawa
Chuo-ku, Tokyo 104-0033
Japan
TEL (81) 3-3523-3551
FAX (81) 3-3523-7581

## Atmel Operations

Atmel Colorado Springs<br>1150 E. Cheyenne Mtn. Blvd.<br>Colorado Springs, CO 80906<br>TEL (719) 576-3300<br>FAX (719) 540-1759

Atmel Rousset
Zone Industrielle
13106 Rousset Cedex
France
TEL (33) 4-4253-6000
FAX (33) 4-4253-6001
Atmel Smart Card ICs
Scottish Enterprise Technology Park
East Kilbride, Scotland G75 0QR
TEL (44) 1355-803-000
FAX (44) 1355-242-743

## Atmel Grenoble

Avenue de Rochepleine
BP 123
38521 Saint-Egreve Cedex
France
TEL (33) 4-7658-3000
FAX (33) 4-7658-3480

Fax-on-Demand<br>North America:<br>1-(800) 292-8635<br>International:<br>1-(408) 441-0732<br>e-mail<br>literature @atmel.com<br>Web Site<br>http://www.atmel.com<br>BBS<br>1-(408) 436-4309

## © Atmel Corporation 2000.

Atmel Corporation makes no warranty for the use of its products, other than those expressly contained in the Company's standard warranty which is detailed in Atmel's Terms and Conditions located on the Company's web site. The Company assumes no responsibility for any errors which may appear in this document, reserves the right to change devices or specifications detailed herein at any time without notice, and does not make any commitment to update the information contained herein. No licenses to patents or other intellectual property of Atmel are granted by the Company in connection with the sale of Atmel products, expressly or by implication. Atmel's products are not authorized for use as critical components in life support devices or systems.
Marks bearing ${ }^{\circledR}$ and/or ${ }^{\text {TM }}$ are registered trademarks and trademarks of Atmel Corporation.
Printed on recycled paper.
Terms and product names in this document may be trademarks of others.

